



Wavefront sensors and adaptive optics for optical metrology, laser and microscopy



OPTICAL METROLOGY



HIGH-POWER LASERS



BIO-IMAGING



X-EUV



**IMAGINE OPTIC
PRESENTS**

**How can wavefront sensing support
AR/VR/MR integration and production?**

”

You can't manage ~~manage~~ **ufacture** what you can't measure

Peter Drucker (?)
management thinker

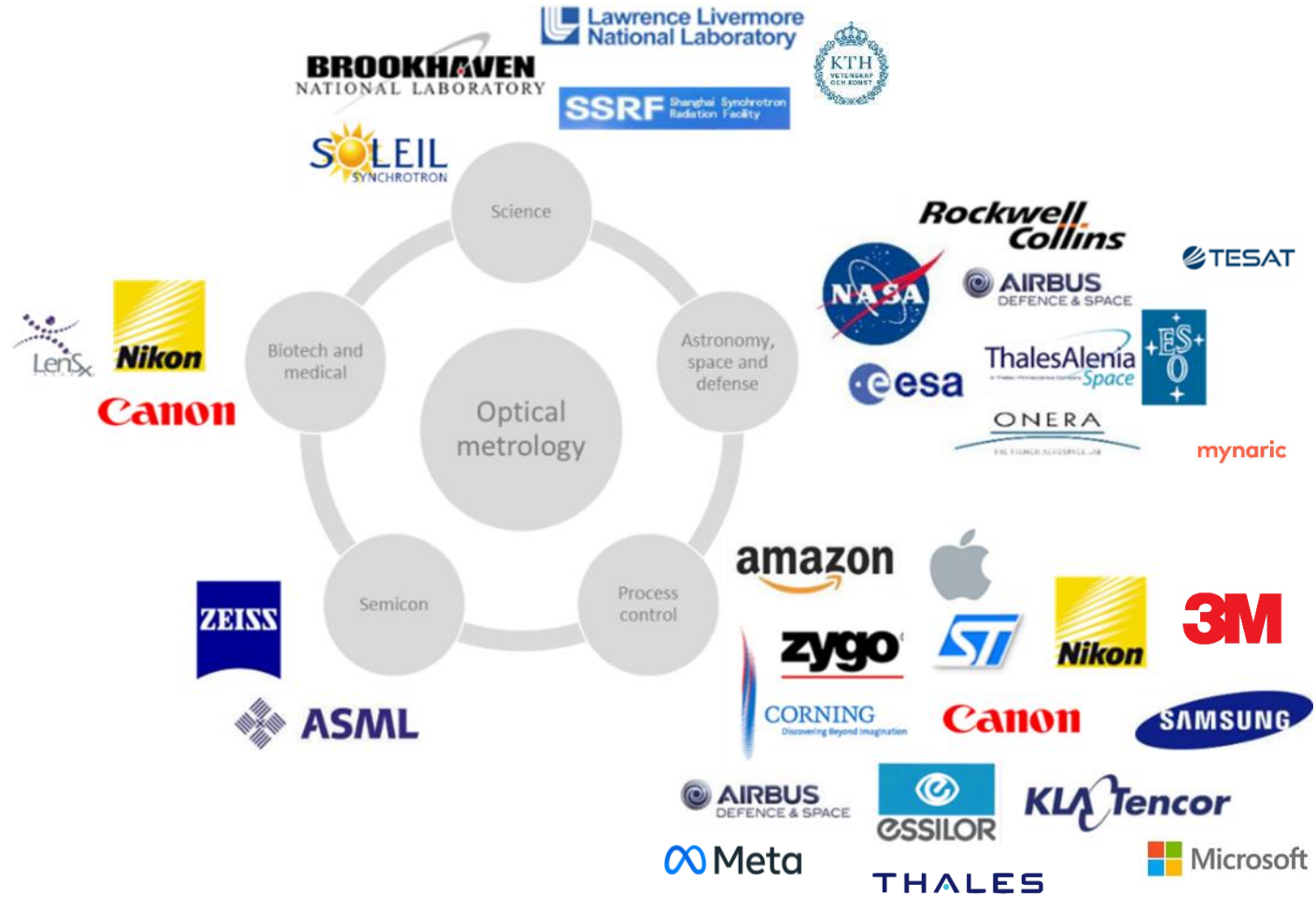
AR/VR components & systems represent a huge (optical) metrology challenge:

- + Very large dynamic ranges
- + Large aperture: large diam./short focal lengths
- + Complex multi-elements systems:
 - AR/TR coatings
 - Polarization control
 - Embedded features (waveguide, etc.)





- + Founded in **1996**, development and manufacturing of **wavefront sensing & adaptive optics**
- + **55** employees, **6.5 M€** revenue
- + 35+ patents granted
- + > **2000 sensors** worldwide...
- + > **200 Adaptive optics** systems with Mirao52e for ophthalmology and microscopy and > **70 adaptive optics** systems with ILAO & ILAO Star for high-power lasers in > 10 countries



(Shack-Hartmann) Wavefront sensing is a metrology technique that provides quantitative metrics on:

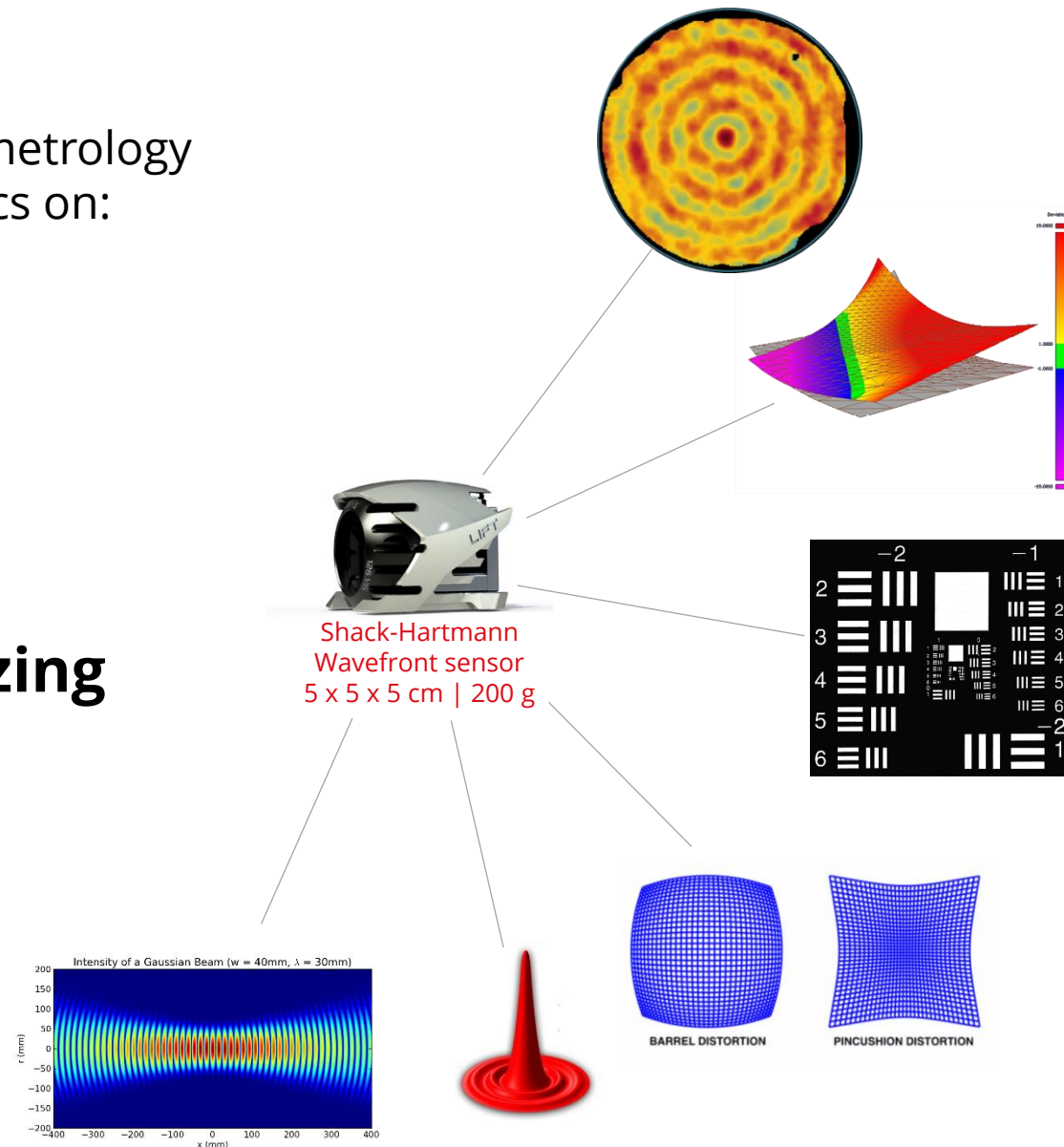
Optical quality

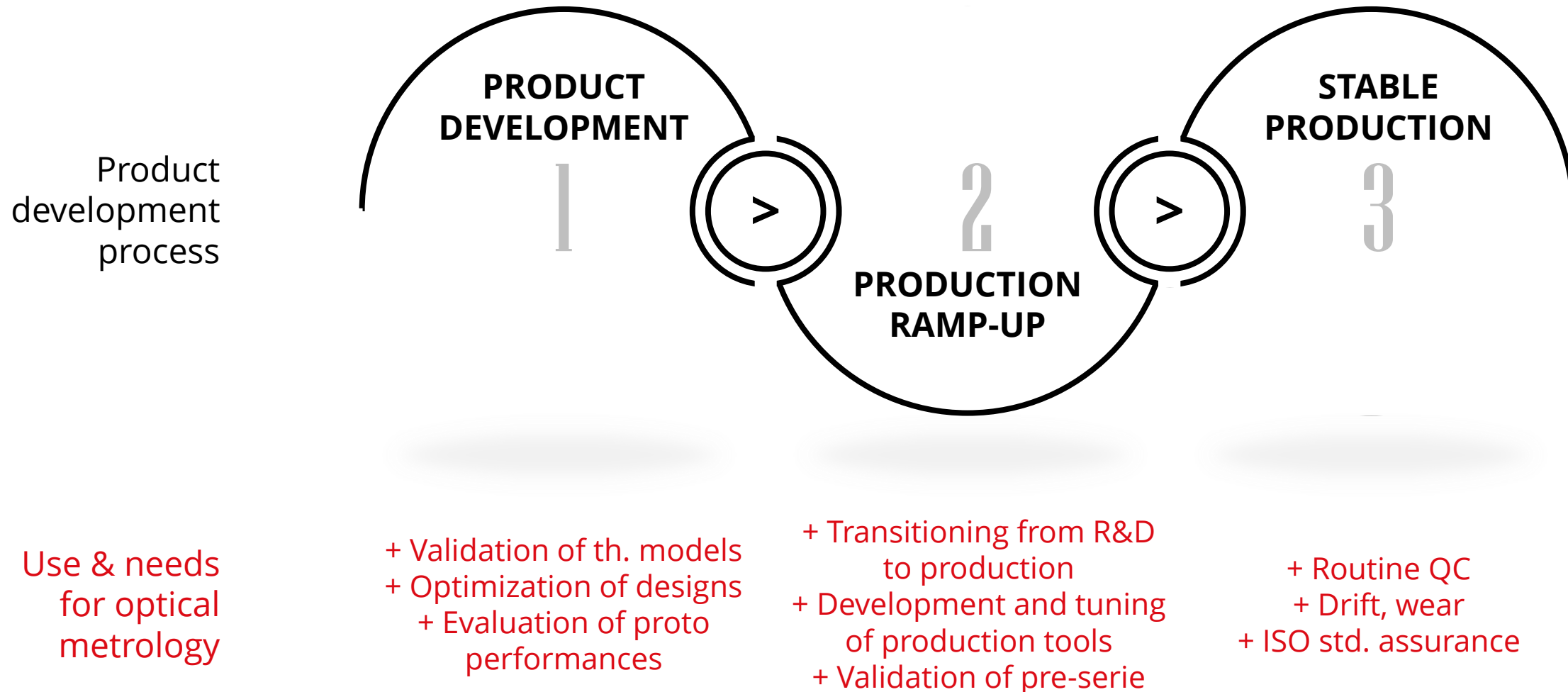
- + Transmitted wavefront error
- + Surface shape / surface deviation
- + MTF
- + Distortion

Mounting / adjusting / optimizing

- + Optical alignment in live
- + Knowledge on source of errors

Laser diagnostic
Adaptive optics control





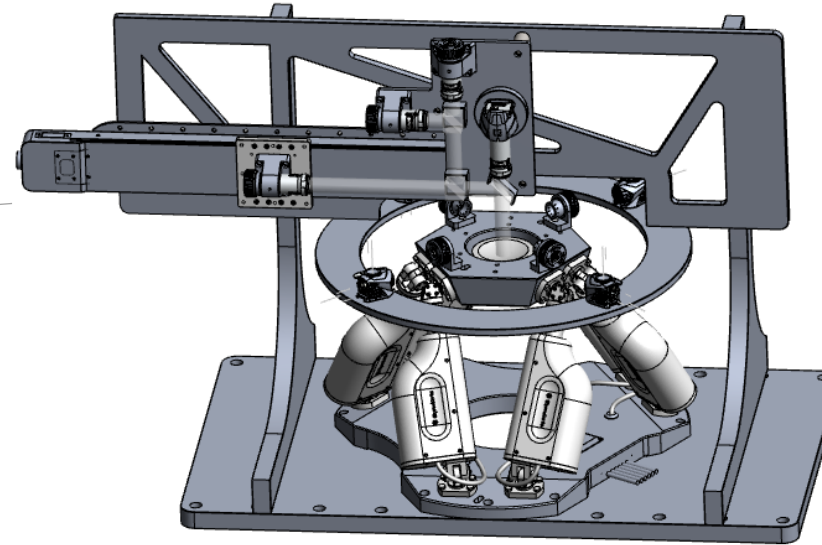
PRODUCT DEVELOPMENT

- + Technical challenge is in general **very high** (complex and new)
 - Use of standard (existing) metrology solutions w/ specific implementation to adapt for specificity of samples
 - Development of new solution
- + Metrology performed by **experts**, highly skilled / trained resources
- + Usually iterative process
- + **Time budget** allocated is very **large**
- + Environment is controlled and optimal

- + Evaluate/validate the metrology means used for the next phases



Off-the-shelf solutions



Very large dynamic range implementations



Specific metrology developments

PRODUCT DEVELOPMENT

PRODUCTION RAMP-UP

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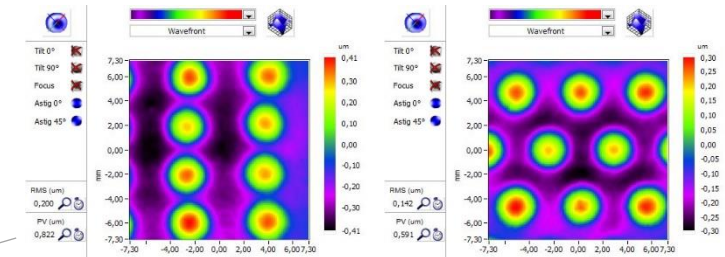
+ Evaluate/validate the metrology means used for the next phases

+ Similar tech. challenge (same kind of technical requirements), but **benefit from previous phase**

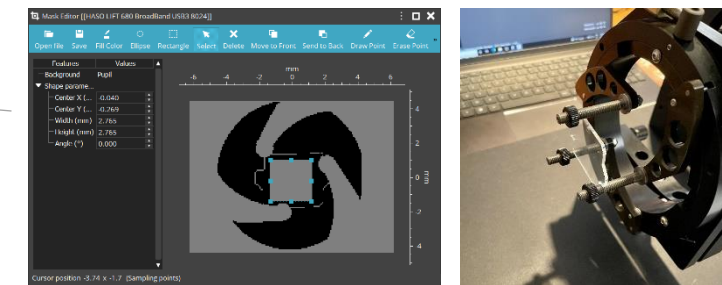
+ Metrology on a different kind of object: for example on mold (shape control and deviation from mold to object molded)

+ Broadly similar

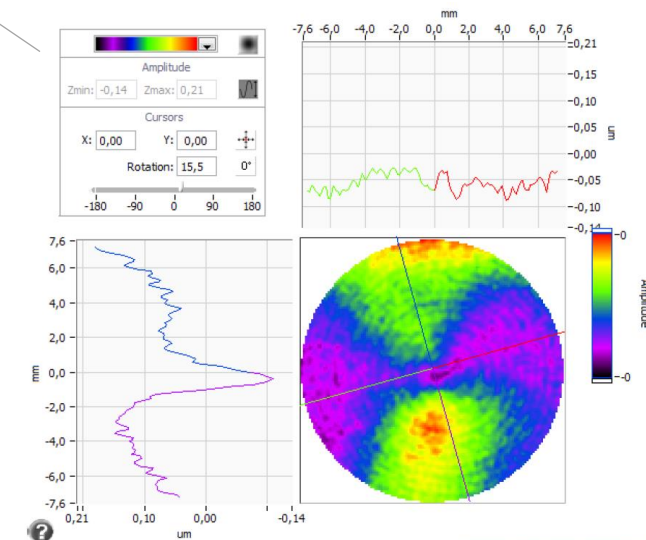
+ Define the metrology means used in stable production



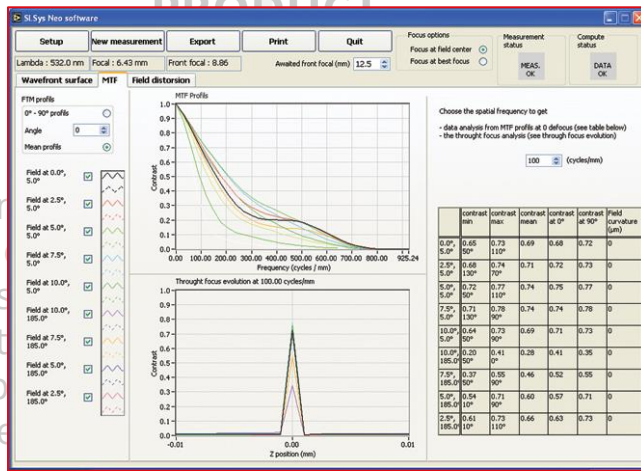
Microstructures characterization on mold



Mold development vs molded object analysis



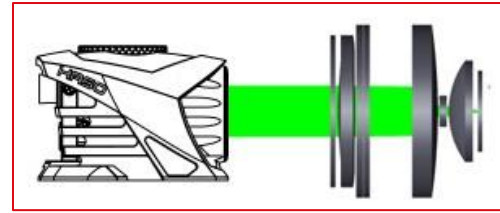
Mold polishing quality testing



Automated test bench for MTF measurement



Automated test bench for focus measurement



Metrology of VR system in user working conditions

+ Similar tech. challenge (same kind of technical requirements), but benefit from previous phase)

Procès-verbal de mesure de [REDACTED]

Informations générales

Date : [REDACTED] Numéro de série : [REDACTED]

Opérateur : [REDACTED]

Commentaire : [REDACTED]

Référence visière : [REDACTED] Numéro de série : [REDACTED]

Informations des colles utilisées		Respect des temps d'attente		
Type de colle	Numéro de lot	Etape 1	Etape 2	Etape 3
		OK/KO	OK/KO	OK/KO
Date d'ouverture	OK/KO			
Date de péremption	OK/KO			

Résultats

Mesuré	Tolérance (<)	Sanction
Décentration X (mm)		
Décentration Y (mm)		
Défocalisation (mm)		
P.V de déformation (µm)		OK/KO
Décentration total (mm)		OK/KO
Diamètre de tâche (mm)		OK/KO

CONFORME / NON CONFORME Référence : Yxxxxxxx Rev : xx

Notes :

Bonding under live optical metrology

STABLE PRODUCTION

- + Measurement can **eventually** be **much simpler** than in the first two stages
 - Use same technology (because already validated)
 - Different implementation
- + Measurements according to **ISO standards**

Fully in production environment:

- + Easy to use by any operators
- + Fast (systematic or sampling)
- + At line
- + Robustness to vibrations
- + Automation: SDKs for software integration in
- + Reactive technical support

xR: technically complex application

=> first challenge to address

Necessary **transitioning through phases** to get to production:

=> Technology supports these phases

=> Technology adapts so that we can inherit from dev. & knowledge acquired

Requirements change through phases

and can eventually simplify in production...

...or not!



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Pleased to provide more information

Happy to perform **tests on your samples**

Support information